



BSI Standards Publication

Semiconductor devices — Micro-electromechanical devices

Part 35: Test method of electrical characteristics under bending deformation for flexible electromechanical devices

National foreword

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The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its committee manager.

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Published by BSI Standards Limited 2021

ISBN 978 0 580 99495 1

ICS 31.080.99

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This British Standard was published under the authority of the Standards Policy and Strategy Committee on 30 April 2021.

Amendments/corrigenda issued since publication

Date	Text affected
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